

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10586292	TEY ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
Pablo N Tran	2618	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
455	347., 300, 301, 293, 349., 130, 191.1, 189.1, 252.1, 253.1, 311-312, 333-334, 90.3, 550.1, 575.1	9/10/08	PT
348	162	9/10/08	PT
257	686, 723, 777, 779, 659, 773, 728, 700, 702, 706, 723-724	9/10/08	PT
343	702, 772	9/10/08	PT
327	356, 359, 355, 566,	9/10/08	PT

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
East/West	9/17/08	PT

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

	/P. N. T./ Primary Examiner, Art Unit 2618
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